



Frontiers in X-ray Materials Analysis
Thursday, October 9, 2014

FXMA Agenda 10/9/14

- 8:30AM - 9:00AM**
9:00AM **Registration**
Welcome by Yale staff person
- 9:00AM - 9:30AM** **Brian Jones, Bruker AXS Inc, Product Manager-XRD**
Recent advances in XRD instrumentation for Materials Analysis
- 9:30AM - 10:00AM** **Michael Beauchaine Bruker XRFi, Business Development Manager**
Materials on a microscopic scale
- 10:00AM - 10:30AM** **Morning Break**
- 10:30AM - 11:00AM** **Mark Rodriguez, Principle Member of Technical Staff**
Sandia National Labs, Albuquerque, NM
Employing micro-XRF for detection of trace phases
- 11:00AM - 11:30AM** **Jim Britten, Manager and Scientific Director, MAX Diffraction Facility,**
McMaster University, Hamilton, ON, Canada
Texture Analyses of ZnTe and CdTe Thin Films Using XRD³,
Jim Britten, Victoria Jarvis, Carley Miki and John Preston
- 11:30AM - 12:00PM** **Jon Giencke, University of Wisconsin, Madison and**
Bruker AXS Inc, Application Scientist
Structural Characterization of Ultra Thin Multiferroic Thin Films with
Lab Based X-ray Diffraction
- 12:00PM - 1:30PM** **Lunch and Tour**
- 1:30PM - 2:00PM** **Daniel Roberts, Research Scientist,**
Bristol-Myers Squibb, New Brunswick, NJ
High Throughput Screening (HTS) applications using XRD
- 2:00PM - 2:30PM** **Dmytro Nykypanchuk, Research Scientist,**
Brookhaven National Lab, Upton, NY
Small Angle X-ray Diffraction Studies of Nanoparticle Self-assembly
- 2:30PM - 3:00PM** **Afternoon Break**
- 3:00PM - 3:30PM** **Chunhua Tony Hu, X-ray Crystallographer,**
New York University, New York, NY
Anti-counterfeit Protection of Pharmaceutical
Products Using a Micro-X-ray Diffraction Protocol
- 3:30PM - 4:00PM** **Shawn Gibb, VP of Engineering Crystal IS, Inc., Green Island, NY**
Characterization of Aluminum Nitride Materials via X-ray Diffraction